

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/758,317	CHANG ET AL.	
Examiner		Art Unit	DuyVu n. Deo	
		1765	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0232491	12-2003	Yamaguchi, Akihisa	438/591
	B	US-6,387,761	05-2002	Shih et al.	438/287
	C	US-2002/0197880	12-2002	Niimi et al.	438/763
	D	US-6,559,007	05-2003	Weimer, Ronald A.	438/257
	E	US-6,649,538	11-2003	Cheng et al.	438/775
	F	US-6,821,868	11-2004	Cheng et al.	438/517
	G	US-6,245,616	06-2001	Buchanan et al.	438/287
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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